#### TOSHIBA Diode Silicon Epitaxial Planar Type

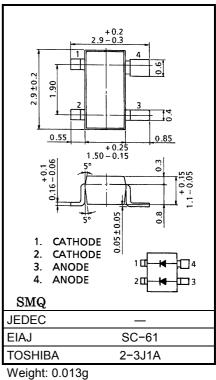
# 1SS272

#### Ultra High Speed Switching Application

- Small package : SC-61
- Low forward voltage : V<sub>F</sub> (3) = 0.92V (typ.)
- Fast reverse recovery time: t<sub>rr</sub> = 1.6ns (typ.)
- Small total capacitance  $: C_T = 0.9 pF$  (typ.)

### Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	Unit	
Maximum (peak) reverse voltage	V <sub>RM</sub>	85	V	
Reverse voltage	V <sub>R</sub>	80	V	
Maximum (peak) forward current	I <sub>FM</sub>	300 (*)	mA	
Average forward current	Ι <sub>Ο</sub>	100 (*)	mA	
Surge current (10ms)	I <sub>FSM</sub>	2 (*)	А	
Power dissipation	Р	150	mW	
Junction temperature	Тј	125	°C	
Storage temperature range	T <sub>stg</sub>	-55~125	°C	

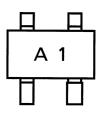


(\*) Unit rating. Total rating = Unit rating  $\times$  1.5.

### **Electrical Characteristics (Ta = 25°C)**

Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Forward voltage	V <sub>F (1)</sub>	-	I <sub>F</sub> = 1mA	_	0.61	-	V
	V <sub>F (2)</sub>	_	I <sub>F</sub> = 10mA	_	0.74	_	
	V <sub>F (3)</sub>	_	I <sub>F</sub> = 100mA	_	0.92	1.20	
Reverse current	I <sub>R (1)</sub>	-	V <sub>R</sub> = 30V	_	_	0.1	μA
	I <sub>R (2)</sub>	_	V <sub>R</sub> = 80V	_	—	0.5	
Total capacitance	CT	_	V <sub>R</sub> = 0, f = 1MH <sub>z</sub>	_	0.9	2.0	pF
Reverse recovery time	t <sub>rr</sub>	—	I <sub>F</sub> = 10mA ,Fig.1		1.6	4.0	ns

### Marking



Unit: mm

## **TOSHIBA**

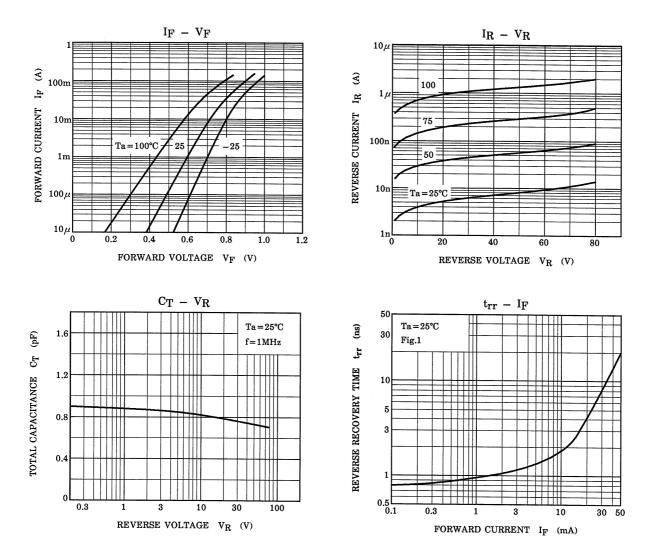
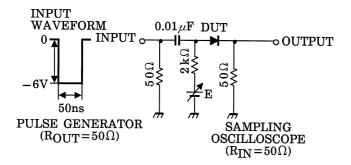
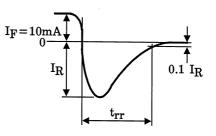


Fig.1 Reverse recovery time (t<sub>rr</sub>) test circuit



OUTPUT WAVEFORM



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